

# **PH6325L** N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK Rev. 2 — 22 December 2011 Product

Product data sheet

#### **Product profile** 1.

#### **1.1 General description**

Logic level N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS<sup>TM</sup> technology

#### 1.2 Features and benefits

- Low thermal resistance
- Low threshold voltage

- Optimized for use in DC-to-DC converters
- Very low switching and conduction losses

### **1.3 Applications**

- DC-to-DC convertors
- Notebook computers

### 1.4 Quick reference data

- Switched-mode power supplies
- Voltage regulators

Table 1.	Quick reference data					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	-	25	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	78.7	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Static cha	racteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 4.5 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	7.4	9.5	mΩ
		$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	4.7	6.3	mΩ
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS}$ = 4.5 V; $I_{D}$ = 25 A; $V_{DS}$ = 12 V; see	-	3.3	-	nC
Q <sub>G(tot)</sub>	total gate charge	Figure 11; see Figure 12	-	13.3	-	nC



## 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		-
2	S	source	mb	
3	S	source		
4	G	gate		
mb	D	mounting base; connected to drain	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	mbb076 S
			SOT669 (LFPAK; Power-SO8)	

# 3. Ordering information

#### Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
PH6325L	LFPAK; Power-SO8	plastic single-ended surface-mounted package; 4 leads	SOT669	

#### **Limiting values** 4.

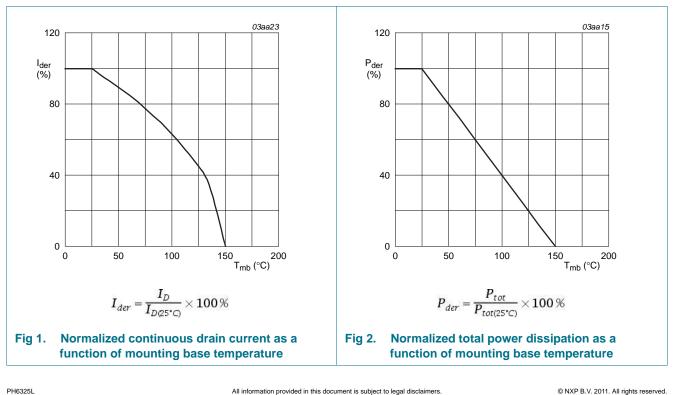
#### **Limiting values** Table 4.

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	25	V
V <sub>GS</sub>	gate-source voltage		-20	20	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; see <u>Figure 1</u>	-	49.6	А
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1;</u> see <u>Figure 3</u>	-	78.7	А
I <sub>DM</sub>	peak drain current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$ ; see Figure 3	-	236	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	62.5	W
T <sub>stg</sub>	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dr	ain diode				
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	-	52	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$	-	208	А
Avalanche	e ruggedness				
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	$t_p$ = 0.015 ms; unclamped; R <sub>GS</sub> = 50 Ω; I <sub>D</sub> = 3.4 A; [1][2] V <sub>DD</sub> = 25 V; V <sub>GS</sub> = 10 V	-	1.2	mJ
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 34 A; $V_{DD}$ = 25 V; $t_p$ = 0.15 ms; unclamped; $R_{GS}$ = 50 $\Omega$	-	115	mJ
-					

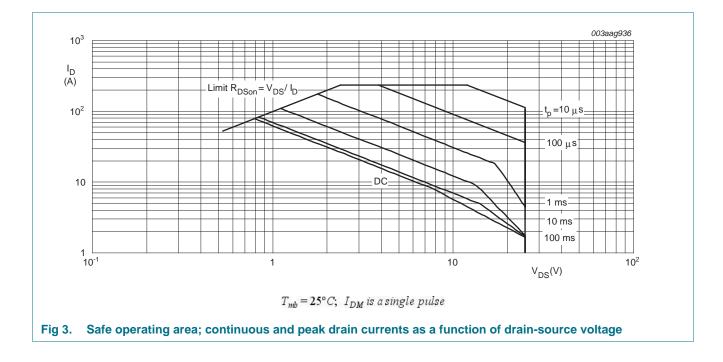
[1] Duty cycle is limited by the maximum junction temperature.

Repetitive avalanche failure is not determined simply by thermal effects. Repetitive avalanche transients should only be applied for short [2] bursts, not every switching cycle.



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#### N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK

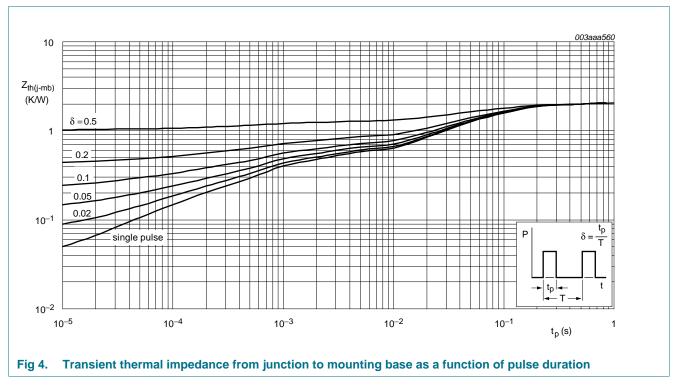


# PH6325L

N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK

### 5. Thermal characteristics

SymbolParameterConditionsMinTypMaxReferencethermal resistance from junction to mounting basesee Figure 42						
Region thermal resistance from junction to mounting base see Figure 4	p Max Unit	Тур	Min	Conditions	Parameter	Symbol
Tth(j-mb) thermal resistance from junction to mounting base see <u>righter</u>	2 K/W	-	-	see Figure 4	thermal resistance from junction to mounting base	R <sub>th(j-mb)</sub>



# PH6325L

N-channel 25 V 6.3 mΩ logic level MOSFET in LFPAK

## 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	25	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	2.2	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 150 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	0.5	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.5	2	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 25 \text{ V};  V_{GS} = 0 \text{ V};  T_j = 25 ^{\circ}\text{C}$	-	0.06	1	μA
		$V_{DS}$ = 25 V; $V_{GS}$ = 0 V; $T_j$ = 150 °C	-	-	500	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = 16 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	10	100	nA
		$V_{GS}$ = -16 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	10	100	nA
$R_{DSon}$	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 150 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	7.5	10.1	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 150 \text{ °C};$ see Figure 9; see Figure 10	-	11.8	15.2	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	7.4	9.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 9; see Figure 10	-	4.7	6.3	mΩ
		<u>ingulo o</u> , oco <u>ingulo ro</u>				
R <sub>G</sub>	internal gate resistance	f = 1 MHz	-	1.8	-	Ω
	internal gate resistance characteristics		-	1.8	-	Ω
	-		-	1.8 13.3	-	Ω nC
Dynamic	characteristics	f = 1 MHz I <sub>D</sub> = 25 A; V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 4.5 V;	-			
Dynamic	characteristics	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$		13.3	-	nC
Dynamic Q <sub>G(tot)</sub>	characteristics total gate charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set	-	13.3 11.1	-	nC nC
Dynamic ( Q <sub>G(tot)</sub>	characteristics total gate charge gate-source charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set	-	13.3 11.1 4.9	-	nC nC nC
Dynamic Q <sub>G(tot)</sub>	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set		13.3 11.1 4.9 2.6	-	nC nC nC nC
Dynamic Q <sub>G(tot)</sub> Q <sub>GS</sub> Q <sub>GS1</sub> Q <sub>GS2</sub>	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ and the set of the set		13.3 11.1 4.9 2.6 2.3	-	nC nC nC nC nC
Dynamic Q <sub>G(tot)</sub> Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub>	characteristics total gate charge gate-source charge pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$	- - - -	<ul> <li>13.3</li> <li>11.1</li> <li>4.9</li> <li>2.6</li> <li>2.3</li> <li>3.3</li> </ul>	-	nC nC nC nC nC nC
Dynamic Q <sub>G(tot)</sub> Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub> V <sub>GS(pl)</sub>	characteristics         total gate charge         gate-source charge         pre-threshold gate-source charge         post-threshold gate-source         charge         gate-drain charge         gate-source plateau voltage	$ \begin{split} f &= 1 \text{ MHz} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ I_D &= 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12; see Figure 12} \\ \\ \\ \\ I_D &= 0 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz; } \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ $	- - - -	13.3 11.1 4.9 2.6 2.3 3.3 2.4	-	nC nC nC nC nC NC V
Dynamic Q <sub>G(tot)</sub> Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub> V <sub>GS(pl)</sub>	characteristics         total gate charge         gate-source charge         pre-threshold gate-source charge         post-threshold gate-source         charge         gate-drain charge         gate-source plateau voltage	$ \begin{split} f &= 1 \text{ MHz} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ see Figure 11; see Figure 12 \\ I_D &= 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V} \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ see Figure 11; see Figure 12 \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ See Figure 11}; \\ see Figure 12 \\ \\ \\ \\ V_{DS} &= 0 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz}; \\ \\ \\ \\ T_j &= 25 \text{ °C}; see Figure 13; \\ \\ \end{split} $	- - - -	<ol> <li>13.3</li> <li>11.1</li> <li>4.9</li> <li>2.6</li> <li>2.3</li> <li>3.3</li> <li>2.4</li> <li>2420</li> </ol>	- - - - - -	nC nC nC nC nC V
Dynamic Q <sub>G</sub> (tot) Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub> V <sub>GS(pl)</sub> C <sub>iss</sub>	characteristics         total gate charge         gate-source charge         pre-threshold gate-source charge         post-threshold gate-source         charge         gate-drain charge         gate-source plateau voltage         input capacitance	$ \begin{split} f &= 1 \text{ MHz} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ I_D &= 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V} \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ V}_{GS} = 4.5 \text{ V}; \\ \text{see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12} \\ \\ \\ I_D &= 25 \text{ A}; \text{ V}_{DS} = 12 \text{ V}; \text{ see Figure 11; see Figure 12; see Figure 12} \\ \\ \\ \\ I_D &= 0 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz; } \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ $	- - - - -	13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 1871	- - - - - - -	nC nC nC nC nC V v
Dynamic Q <sub>G</sub> (tot) Q <sub>GS</sub> Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub> V <sub>GS(pl)</sub> C <sub>iss</sub> C <sub>oss</sub>	characteristics         total gate charge         gate-source charge         pre-threshold gate-source charge         post-threshold gate-source         charge         gate-drain charge         gate-source plateau voltage         input capacitance         output capacitance	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$ see Figure 12 $V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; \text{ see Figure 13};$ see Figure 14 $V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	- - - - - -	<ol> <li>13.3</li> <li>11.1</li> <li>4.9</li> <li>2.6</li> <li>2.3</li> <li>3.3</li> <li>2.4</li> <li>2420</li> <li>1871</li> <li>517</li> </ol>	- - - - - - -	nC nC nC nC nC V pF pF
Dynamic Q <sub>G</sub> (tot) Q <sub>GS</sub> Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub> V <sub>GS</sub> (pl) C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	characteristics         total gate charge         gate-source charge         pre-threshold gate-source charge         post-threshold gate-source         charge         gate-drain charge         gate-source plateau voltage         input capacitance         output capacitance         reverse transfer capacitance	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$ see Figure 12 $V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; \text{ see Figure 13};$ see Figure 14	- - - - - - - -	13.3 11.1 4.9 2.6 2.3 3.3 2.4 2420 1871 517 179	- - - - - - - - - - -	nC nC nC nC nC v pF pF pF
Dynamic Q <sub>G</sub> (tot) Q <sub>GS</sub> Q <sub>GS1</sub> Q <sub>GS2</sub> Q <sub>GD</sub> V <sub>GS(pl)</sub> C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> t <sub>d(on)</sub>	characteristics         total gate charge         gate-source charge         pre-threshold gate-source charge         post-threshold gate-source         charge         gate-drain charge         gate-source plateau voltage         input capacitance         reverse transfer capacitance         turn-on delay time	$f = 1 \text{ MHz}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 11; see Figure 12 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 11};$ see Figure 12 $V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; \text{ see Figure 13};$ see Figure 14 $V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	- - - - - - - -	<ol> <li>13.3</li> <li>11.1</li> <li>4.9</li> <li>2.6</li> <li>2.3</li> <li>3.3</li> <li>2.4</li> <li>2420</li> <li>1871</li> <li>517</li> <li>179</li> <li>25</li> </ol>	- - - - - - - - - -	nC nC nC nC nC V pF pF pF pF ns

Symbol

Source-drain diode

# **PH6325L**

Max

Unit

#### N-channel 25 V 6.3 m $\Omega$ logic level MOSFET in LFPAK

Min

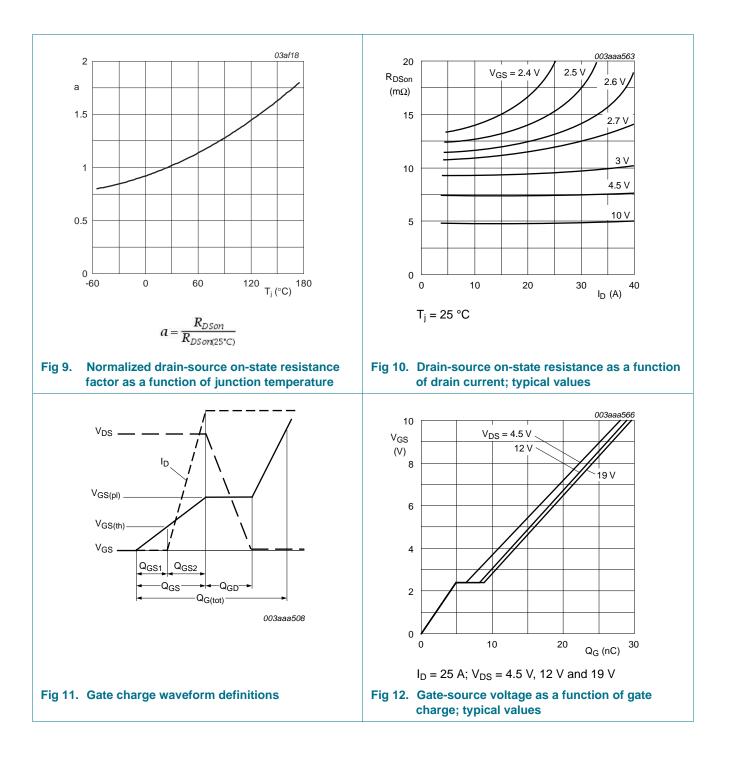
Тур

V <sub>SD</sub>	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>GS</sub> see <u>Figure 15</u>	= 0 V; $T_j$ = 25 °C;	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time		dt = -100 A/µs;	-	33	-	ns
Qr	recovered charge	$V_{GS} = 0 V; V_{DS}$	<sub>S</sub> = 25 V	-	13	-	nC
4 I <sub>D</sub> (A) 3	10 V 4.5 V 2.7 V V <sub>C</sub>	003aaa561 3S = 2.6 V 2.5 V 2.4 V	40 I <sub>D</sub> (A) 30			03aaa562	
2	0	2.3 V 2.2 V 2.1 V	20	T <sub>j</sub> = 150 °C	25 °C		
1		2 V 1.8 V 1.6 V	10				
	0 0.5 1 1	.5 <sub>VDS</sub> (V) <sup>2</sup>	0	1		s (V) <sup>3</sup>	
Fig 5.	T <sub>j</sub> = 25 °C Output characteristics: drain function of drain-source volta		Fig 6. Transfer ch	nd 150 °C; V <sub>D</sub> aracteristics gate-source	: drain c	urrent	
2 V <sub>GS(</sub> (V)	th)	03aa33	10 <sup>-1</sup> I <sub>D</sub> (A) 10 <sup>-2</sup>			3aa36	
1	1 min	```````````````````````````````````````	10 <sup>-3</sup>	min 1/2 typ 2/2	max		
0	.5		10 <sup>-5</sup>				
	0 -60 0 60 12	20 180 T <sub>j</sub> (°C)	10 <sup>-6</sup> /	1 1	2 V <sub>G</sub>	3 3 (V)	
			T <sub>j</sub> = 25 °C; ∖	/ <sub>DS</sub> = 5 V			
	$I_D = 1 m A; V_{DS} = V_G.$	S	,				

Conditions

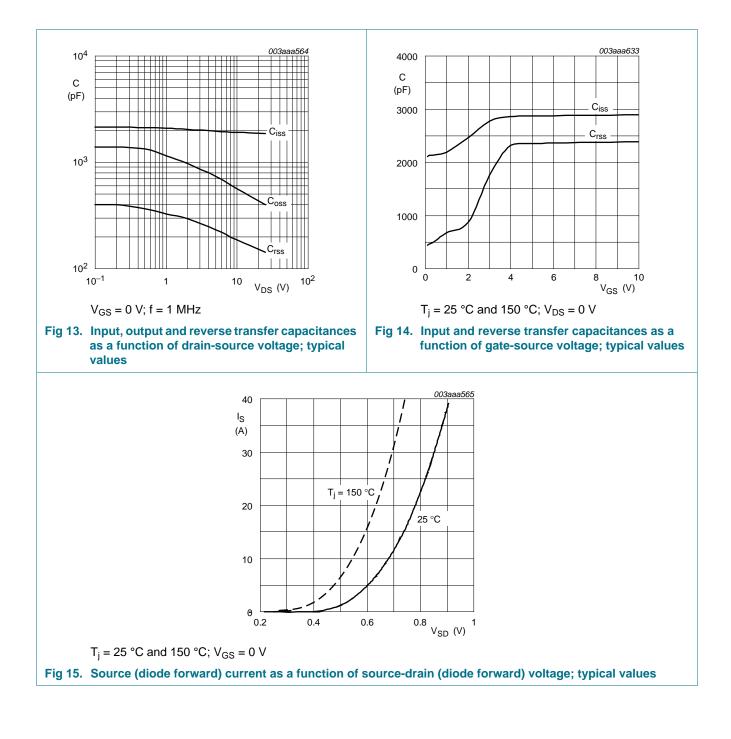
# PH6325L

#### N-channel 25 V 6.3 m $\Omega$ logic level MOSFET in LFPAK



# PH6325L

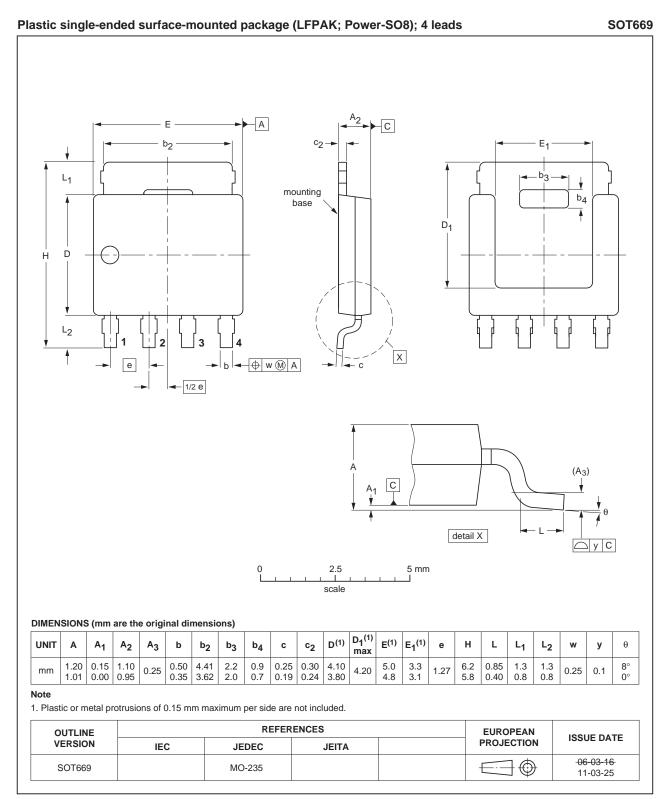
#### N-channel 25 V 6.3 m $\Omega$ logic level MOSFET in LFPAK



# PH6325L

#### N-channel 25 V 6.3 m $\Omega$ logic level MOSFET in LFPAK

### 7. Package outline



#### Fig 16. Package outline SOT669 (LFPAK; Power-SO8)

All information provided in this document is subject to legal disclaimers.

## 8. Revision history

Table 7. Rev	ision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes		
PH6325L v.2	20111222	Product data sheet	-	PH6325L v.1		
Modifications:		<ul> <li>The format of this document has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>				
	<ul> <li>Legal texts have</li> </ul>	ve been adapted to the new	company name where	appropriate.		
	<ul> <li>Status changed</li> </ul>	d from preliminary to produc	t.			
PH6325L v.1	20040428	Preliminary data shee	t -	-		

### 9. Legal information

#### 9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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#### N-channel 25 V 6.3 m $\Omega$ logic level MOSFET in LFPAK

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